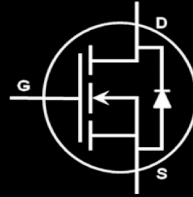


EPC2007C – Enhancement Mode Power Transistor

 $V_{DSS}, 100\text{ V}$
 $R_{DS(on)}, 30\text{ m}\Omega$
 $I_D, 6\text{ A}$

NEW PRODUCT



RoHS

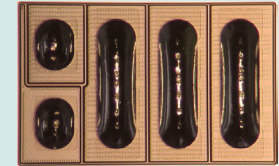


Halogen-Free

Gallium Nitride is grown on Silicon Wafers and processed using standard CMOS equipment leveraging the infrastructure that has been developed over the last 55 years. GaN's exceptionally high electron mobility and low temperature coefficient allows very low $R_{DS(on)}$, while its lateral device structure and majority carrier diode provide exceptionally low Q_G and zero Q_{RR} . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

Maximum Ratings

V_{DS}	Drain-to-Source Voltage (Continuous)	100	V
I_D	Continuous ($T_A = 25^\circ\text{C}$, $R_{\theta JA} = 62^\circ\text{C/W}$)	6	A
	Pulsed (25°C , $T_{Pulse} = 300\ \mu\text{s}$)	40	
V_{GS}	Gate-to-Source Voltage	6	V
	Gate-to-Source Voltage	-4	
T_J	Operating Temperature	-40 to 150	$^\circ\text{C}$
T_{STG}	Storage Temperature	-40 to 150	



EPC2007C eGaN® FETs are supplied only in passivated die form with solder bumps

Applications

- High Speed DC-DC conversion
- Class-D Audio
- High Frequency Hard-Switching and Soft-Switching Circuits

Benefits

- Ultra High Efficiency
- Ultra Low $R_{DS(on)}$
- Ultra low Q_G
- Ultra small footprint

www.epc-co.com/epc/Products/eGaNfets/EPC2007C.aspx

Static Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise stated)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
BV_{DSS}	Drain-to-Source Voltage	$V_{GS} = 0\text{ V}$, $I_D = 75\ \mu\text{A}$	100		V	
I_{DSS}	Drain Source Leakage	$V_{DS} = 80\text{ V}$, $V_{GS} = 0\text{ V}$	20	60	μA	
I_{GSS}	Gate-to-Source Forward Leakage	$V_{GS} = 5\text{ V}$	0.25	2	mA	
	Gate-to-Source Reverse Leakage	$V_{GS} = -4\text{ V}$	20	60	μA	
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 1.2\text{ mA}$	0.8	1.4	2.5	V
$R_{DS(on)}$	Drain-Source On Resistance	$V_{GS} = 5\text{ V}$, $I_D = 6\text{ A}$	24	30	m Ω	
V_{SD}	Source-Drain Forward Voltage	$I_S = 0.5\text{ A}$, $V_{GS} = 0\text{ V}$	2.1		V	

All measurements were done with substrate shorted to source.

Thermal Characteristics

		TYP	UNIT
$R_{\theta JC}$	Thermal Resistance, Junction to Case	3.6	$^\circ\text{C/W}$
$R_{\theta JB}$	Thermal Resistance, Junction to Board	9.3	$^\circ\text{C/W}$
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1)	80	$^\circ\text{C/W}$

Note 1: $R_{\theta JA}$ is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See http://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf for details.

Dynamic Characteristics (T_J = 25°C unless otherwise stated)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
C _{ISS}	Input Capacitance	V _{DS} = 50 V, V _{GS} = 0 V		170	220	pF
C _{OSS}	Output Capacitance			110	165	
C _{RSS}	Reverse Transfer Capacitance			1.9	2.7	
R _G	Gate Resistance			0.4		Ω
Q _G	Total Gate Charge	V _{DS} = 50 V, V _{GS} = 5 V, I _D = 6 A		1.6	2.2	nC
Q _{GS}	Gate-to-Source Charge	V _{DS} = 50 V, I _D = 6 A		0.6		
Q _{GD}	Gate-to-Drain Charge			0.3	0.6	
Q _{G(TH)}	Gate Charge at Threshold			0.4		
Q _{OSS}	Output Charge	V _{DS} = 50 V, V _{GS} = 0 V		8.3	12.5	
Q _{RR}	Source-Drain Recovery Charge			0		

All measurements were done with substrate shorted to source.

Figure 1: Typical Output Characteristics at 25 °C

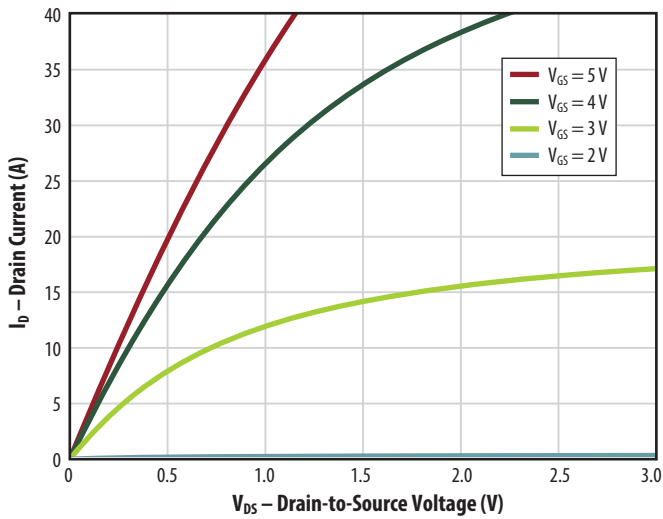


Figure 2: Transfer Characteristics

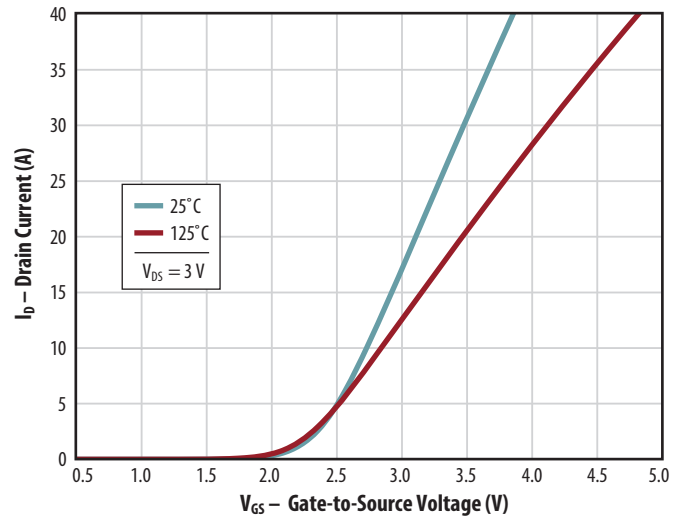


Figure 3: R_{DS(on)} vs. V_{GS} for Various Drain Currents

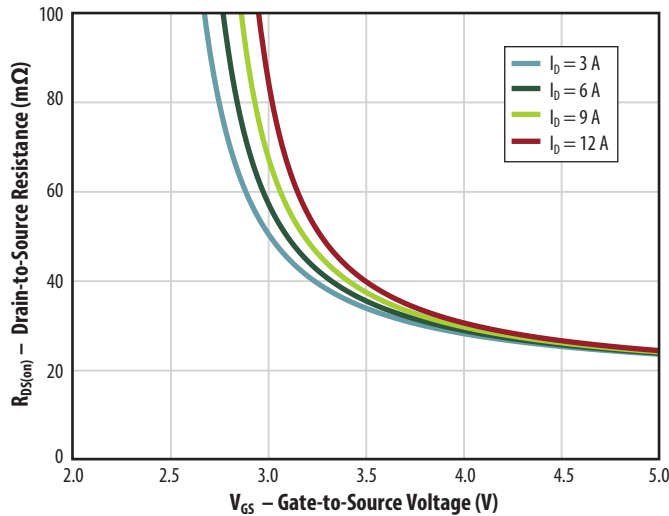


Figure 4: R_{DS(on)} vs. V_{GS} for Various Temperatures

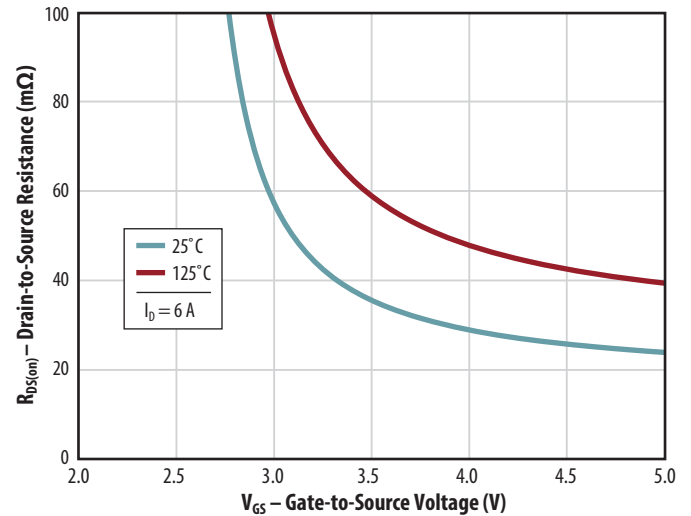


Figure 5a: Capacitance (Linear Scale)

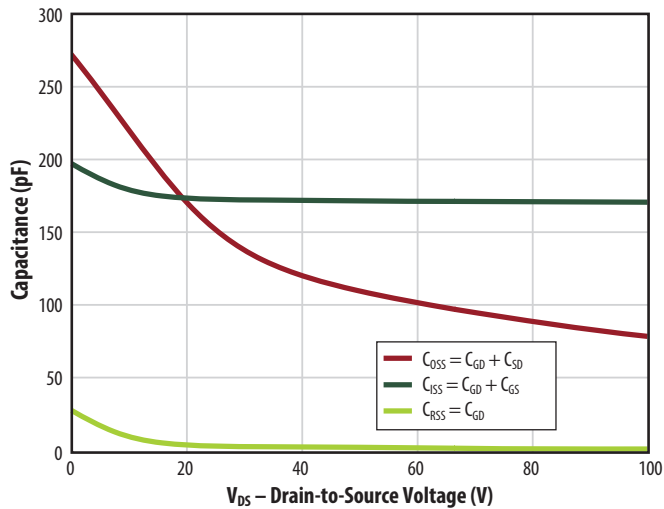


Figure 5b: Capacitance (Log Scale)

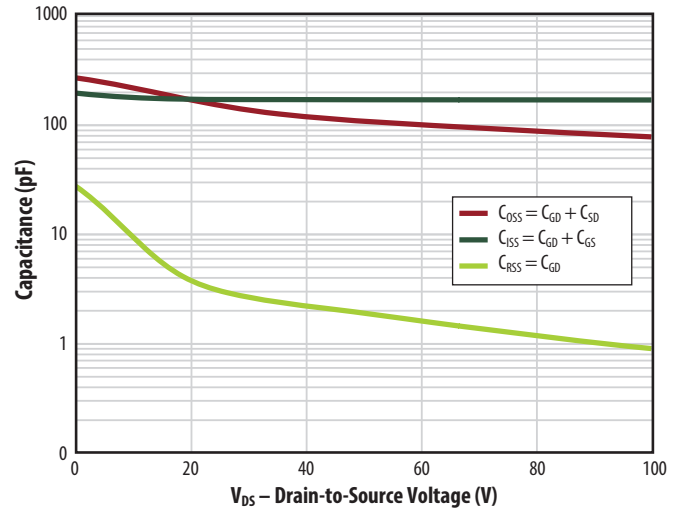


Figure 6: Gate Charge

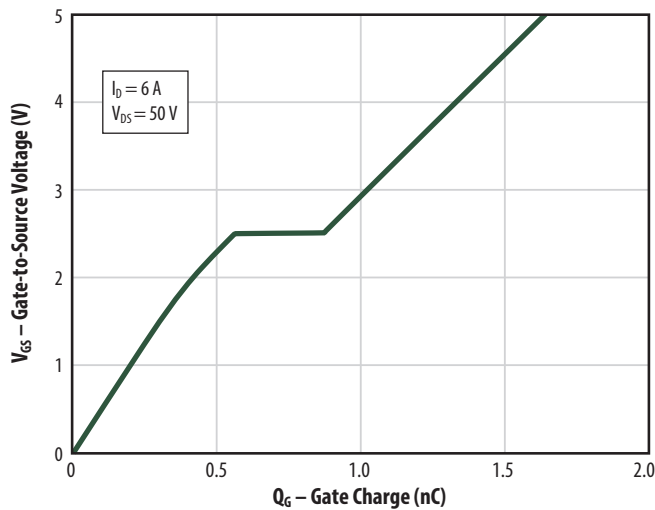


Figure 7: Reverse Drain-Source Characteristics

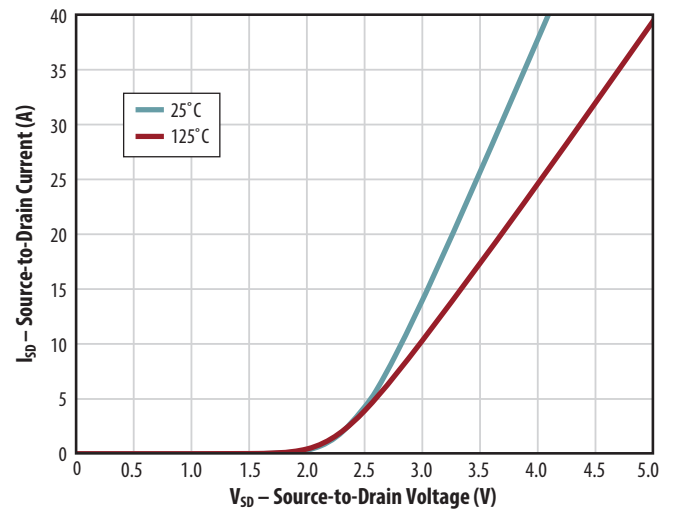


Figure 8: Normalized On-State Resistance vs. Temperature

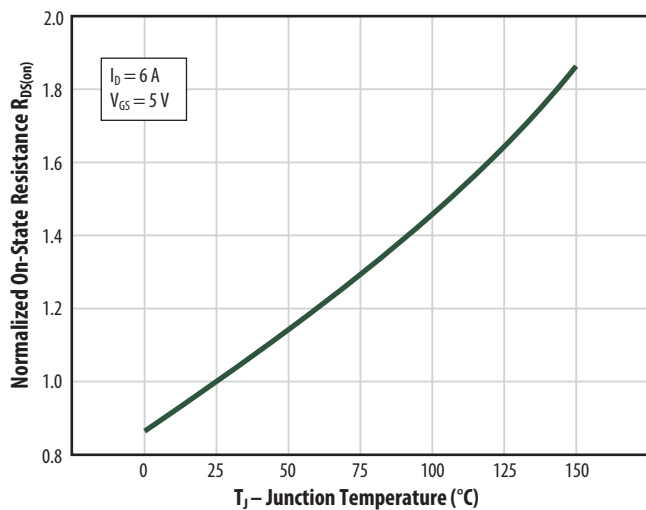
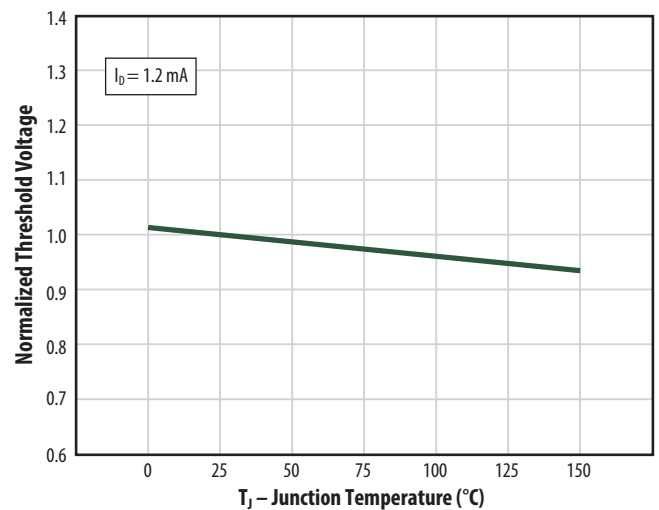


Figure 9: Normalized Threshold Voltage vs. Temperature



All measurements were done with substrate shorted to source.

Figure 10: Gate Leakage Current

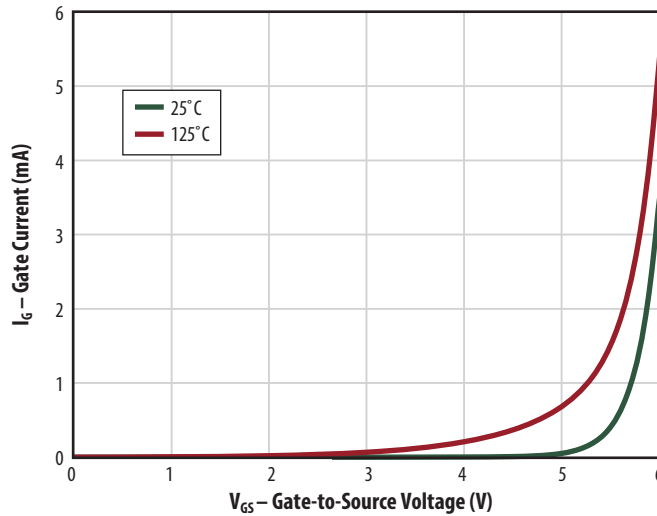


Figure 11: Transient Thermal Response Curves

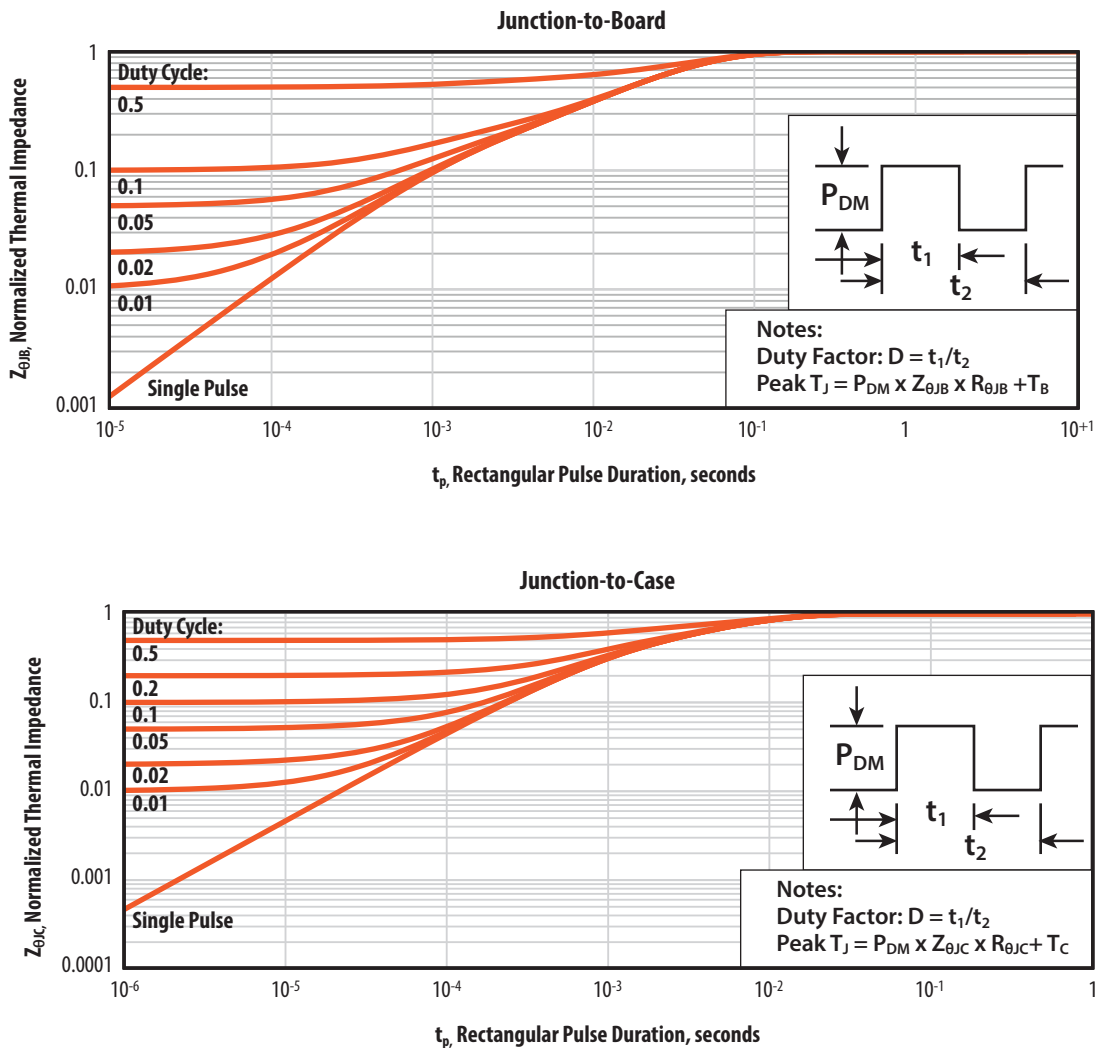
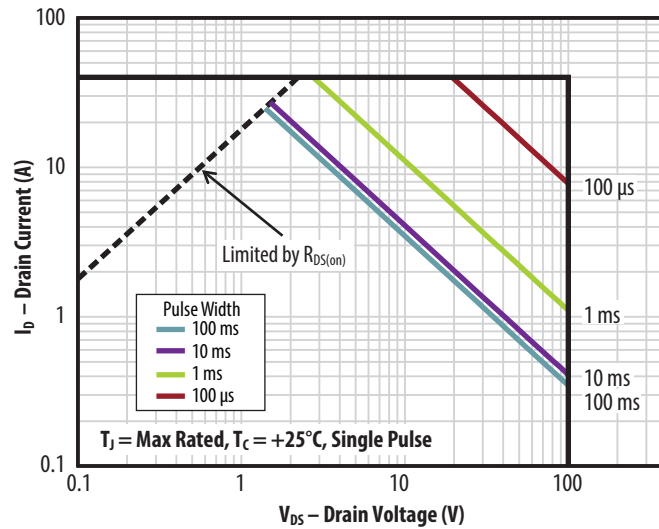
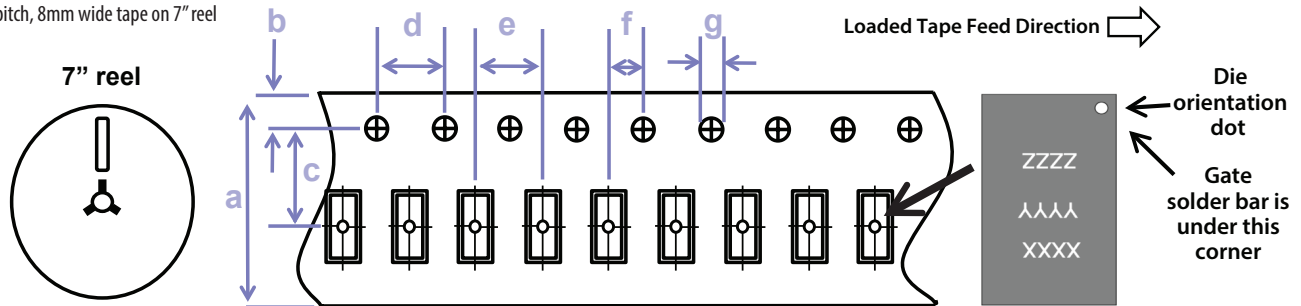


Figure 12: Safe Operating Area



TAPE AND REEL CONFIGURATION

4mm pitch, 8mm wide tape on 7" reel

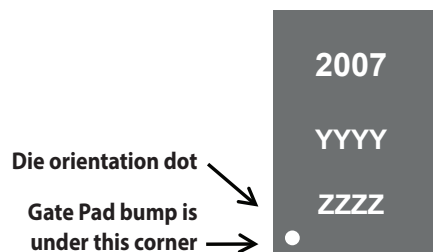


	EPC2007C (note 1)		
Dimension (mm)	target	min	max
a	8.00	7.90	8.30
b	1.75	1.65	1.85
c (see note)	3.50	3.45	3.55
d	4.00	3.90	4.10
e	4.00	3.90	4.10
f (see note)	2.00	1.95	2.05
g	1.5	1.5	1.6

Die is placed into pocket solder bar side down (face side down)

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/JEDEC industry standard.
 Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

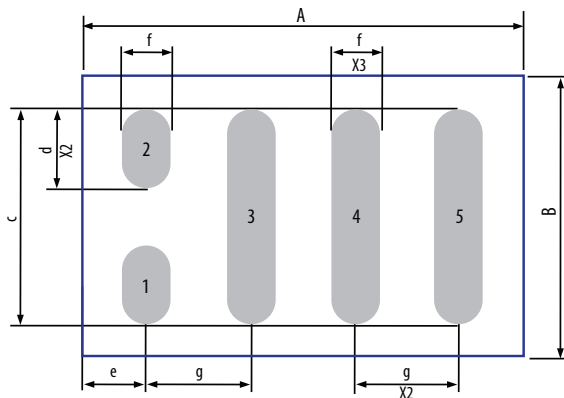
DIE MARKINGS



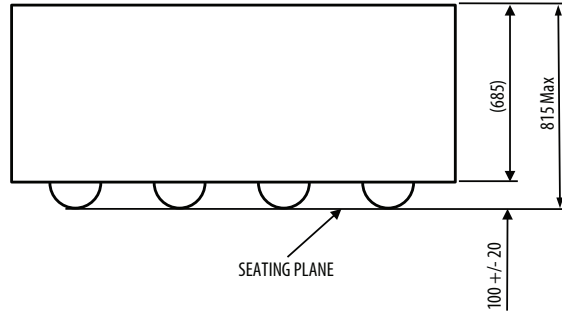
Part Number	Laser Markings		
	Part # Marking Line 1	Lot_Date Code Marking line 2	Lot_Date Code Marking Line 3
EPC2007C	2007	YYYY	ZZZZ

DIE OUTLINE

Solder Bar View



Side View

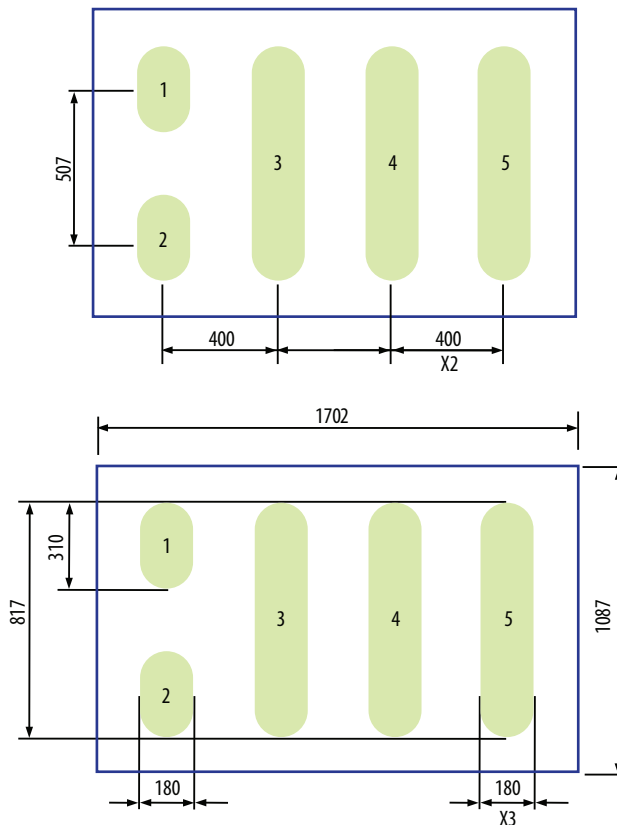


DIM	MICROMETERS		
	MIN	Nominal	MAX
A	1672	1702	1732
B	1057	1087	1117
c	834	837	840
d	327	330	333
e	235	250	265
f	195	200	205
g	400	400	400

RECOMMENDED LAND PATTERN

(measurements in μm)

The land pattern is solder mask defined
Solder mask is 10 μm smaller per side than bump



- Pad no. 1 is Gate
- Pad no. 2 is Substrate
- Pad no. 3 and 5 are Drain
- Pad no. 4 is Source

For assembly recommendations please visit <http://epc-co.com/epc/DesignSupport/AssemblyBasics.aspx>

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U.S. Patents 8,350,294; 8,404,508; 8,431,960; 8,436,398

Information subject to change without notice.
revised January, 2015